# A Complete Bibliography of Publications in *Technometrics* for the decade 2000–2009

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## Title word cross-reference

1 [OH05]. 12 [MS01]. $2^{k-p}$ [BH00, LM02, MP00]. $2^{m-p}$ [KT03]. **\$69.95** [Zie01-52]. $80^{\rm th}$ [Gho07]. $C_P$ [Mal00]. $D$ [GV03, Mit00]. $E(s^2)$ [NC08]. $F$ [Ano00e, SBD98]. $g$ [FG06]. $h$ [FG06]. $K$ [SC04, CFP08, LD04]. $m$ [BG06]. $\mu$ [BGD05]. $n$ [CFP08]. $p$ [BG06, MW05]. $r$ [BG06]. $T^2$ [CJFR05].

[**?**]and-Field:2006:MD. **-circulant** [LD04]. **-Control** [BGD05]. **-Means** [SC04]. **-Optimal** [GV03, Mit00, NC08]. [**?**]out-of-Carreras:2008:RSD. **-Run** [MS01].

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**1900** [Zie00o].

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